Supplementary Information

Preferential phonon scattering and low energy carrier filtering by interfaces of *in-situ* formed InSb nanoprecipitates and GaSb nanoinclusions for enhanced thermoelectric performance in In_{0.2}Co₄Sb₁₂

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Figure S1 (a)SE micrograph, (b) BSE micrograph of (GaSb)_{0.2}+In_{0.2}Co₄Sb₁₂, EPMA-WDS elemental mapping of (c) Co, (d) Sb, (e) In, (f) Ga and (f) O.



Figure S2 Inverse pole figure (IPF) map of (a) Co₄Sb₁₂, (b) InSb and GaSb phase showing grain size and their distribution, normal direction (ND) IPF of (c) Co₄Sb₁₂, (d) GaSb and InSb phase of (GaSb)_{0.1}+In_{0.2}Co₄Sb₁₂.



Figure S3 Rietveld refinement analysis of powder XRD pattern of ball-milled GaSb.



Figure S4 Rietveld refinement analysis of powder XRD pattern of In_{0.2}Co₄Sb₁₂.

Atom	Wyckoff	Х	у	Z	$U_{iso}(Å^2)$	Normalized
	site					site
						occupancy
Со	8c	0.25	0.25	0.25	0.009(1)	1
Sb	24g	0	0.15(7)	0.33(6)	0.005(6)	1
In	2a	0	0	0	0.029(5)	0.24(9)

Table S1 Rietveld refinement parameters of matrix $In_{0.2}Co_4Sb_{12}$.

The composition of the matrix from Rietveld refinement: $In_{0.24(9)}Co_4Sb_{12}$.

Table S2 Rietveld refinement parameters of (GaSb)_{0.1}+In_{0.2}Co₄Sb₁₂.

Atom	Wyckoff	Х	у	Z	$U_{iso}(Å^2)$	Normalized
	site					site
						occupancy
Со	8c	0.25	0.25	0.25	0.004(2)	1
Sb	24g	0	0.15(7)	0.33(5)	0.006(3)	0.97(3)
In	2a	0	0	0	0.068(1)	0.26(4)

The composition of the primary phase of the composite from Rietveld refinement: $In_{0.26(4)}Co_4Sb_{11.67(9)}$.



Figure S5 Rietveld refinement analysis of powder XRD pattern of (GaSb)_{0.2}+In_{0.2}Co₄Sb₁₂.

Atom	Wyckoff	Х	у	Z	$U_{iso}(Å^2)$	Normalized
	site					site
						occupancy
Co	8c	0.25	0.25	0.25	0.006(1)	1
Sb	24g	0	0.15(8)	0.33(4)	0.006(1)	0.97(8)
In	2a	0	0	0	0.043(6)	0.22(5)

Table S3 Rietveld refinement parameters of (GaSb)_{0.2}+In_{0.2}Co₄Sb₁₂.

The composition of the primary phase of the composite from Rietveld refinement: $In_{0.22(5)}Co_4Sb_{11.74(1)}$.



Figure S6 Rietveld refinement analysis of powder XRD pattern of (GaSb)_{0.3}+In_{0.2}Co₄Sb₁₂.

Table S4 Rietveld refinement	parameters of	$(GaSb)_{0.3}+In_{0.2}Co_4Sb_{12}$.

Atom	Wyckoff	Х	у	Z	$U_{iso}(Å^2)$	Normalized
	site					site
						occupancy
Со	8c	0.25	0.25	0.25	0.009(6)	1
Sb	24g	0	0.15(7)	0.33(5)	0.005(3)	0.99(1)
In	2a	0	0	0	0.015(9)	0.23(5)

The composition of the primary phase of the composite from Rietveld refinement: $In_{0.23(5)}Co_4Sb_{11.88(9)}$.



Figure S7 Rietveld refinement analysis of powder XRD pattern of (GaSb)_{0.4}+In_{0.2}Co₄Sb₁₂.

Table S5 Rietveld refinement parameters of (GaSb)_{0.4}+In_{0.2}Co₄Sb₁₂.

Atom	Wyckoff	Х	у	Z	U _{iso} (Å ²)	Normalized
	site					site
						occupancy
Со	8c	0.25	0.25	0.25	0.007(5)	1
Sb	24g	0	0.15(7)	0.33(4)	0.006(2)	0.98(3)
In	2a	0	0	0	0.053(9)	0.20(3)

The composition of the primary phase of the composite from Rietveld refinement: $In_{0.20(3)}Co_4Sb_{11.80(1)}$.



Figure S8 Temperature dependence of electrical resistivity of (GaSb)_{0.1}+In_{0.2}Co₄Sb₁₂.



Figure S9 Temperature dependence of Seebeck coefficient of (GaSb)_{0.1}+In_{0.2}Co₄Sb₁₂.



Figure S10 Temperature dependence of power factor of (GaSb)_{0.1}+In_{0.2}Co₄Sb₁₂.